

Application/Control No.	Applicant(s)/Patent under Reexamination
09/680,177	OSHIMA ET AL.
Examiner	Art Unit
Dac V. Ha	2634

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

DATE EXM	SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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